

VERY LOW POWER, NEGATIVE RAIL INPUT, RAIL-TO-RAIL OUTPUT, FULLY DIFFERENTIAL AMPLIFIER

Check for Samples: THS4524-EP

FEATURES

- Fully Differential Architecture
- Bandwidth: 145 MHz
- Slew Rate: 490 V/µs
- HD_2 : -133 dBc at 10 kHz (1 V_{RMS} , $R_L = 1 k\Omega$)
- HD_3 : -140 dBc at 10 kHz (1 V_{RMS} , $R_L = 1 k\Omega$)
- Input Voltage Noise: 4.6 nV/√Hz (f = 100 kHz)
- THD+N: -112dBc (0.00025%) at 1 kHz (22-kHz BW, G = 1, 5 V_{PP})
- · Open-Loop Gain: 119 dB
- NRI—Negative Rail Input
- RRO—Rail-to-Rail Output
- Output Common-Mode Control (With Low Offset and Drift)
- Power Supply:
 - Voltage: +2.5 V (±1.25 V) to +5.5 V (±2.75 V)
 - Current: 1.14 mA/ch
- Power-Down Capability: 20 µA (Typical)

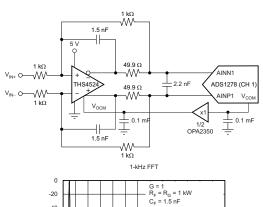
APPLICATIONS

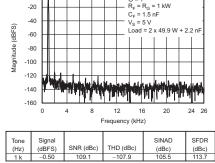
- Low-Power SAR and ΔΣ ADC Drivers
- Low-Power Differential Drivers
- Low-Power Differential Signal Conditioning
- Low-Power, High-Performance Differential Audio Amplifiers

SUPPORTS DEFENSE, AEROSPACE, AND MEDICAL APPLICATIONS

- Controlled Baseline
- One Assembly/Test Site
- One Fabrication Site
- Available in Military (–55°C/125°C)
 Temperature Range (1)
- Extended Product Life Cycle
- Extended Product-Change Notification
- Product Traceability

THS4524 and ADS1278 Combined Performance





(1) Additional temperature ranges available - contact factory

DESCRIPTION

The THS4524 is a very low-power, fully differential operational amplifier with rail-to-rail output and an input common-mode range that includes the negative rail. This amplifier is designed for low-power data acquisition systems and high-density applications where power dissipation is a critical parameter, and provide exceptional performance in audio applications.

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This fully differential op amp features accurate output common-mode control that allows for dc-coupling when driving analog-to-digital converters (ADCs). This control, coupled with an input common-mode range below the negative rail as well as rail-to-rail output, allows for easy interfacing between single-ended, ground-referenced signal sources. Additionally, the THS4524 is ideally suited for driving both successive-approximation register (SAR) and delta-sigma ($\Delta\Sigma$) ADCs using only a single +2.5-V to +5-V and ground power supply.

The THS4524 fully differential op amp is characterized for operation over the full industrial temperature range from -55°C to 125°C.

RELATED PRODUCTS

DEVICE	BW (MHz)	I _Q (mA)	THD (dBc) at 100 kHz	V _N (nV/√ Hz)	RAIL-TO-RAIL
THS4520	570	15.3	-114	2	Out
THS4121	100	16	-79	5.4	In/Out
THS4130	150	16	-107	1.3	No





This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

PACKAGE/ORDERING INFORMATION(1)

T _A	PACKAGE-LEAD	PACKAGE D	ESIGNATOR	ORDERABLE PART NUMBER	TOP-SIDE MARKING	VID NUMBER
-55°C to 125°C	TSSOP - 38	DBT	Tape and reel, 2000	THS4524MDBTREP	THS4524EP	V62/12612-01XE
			Rails, 50	THS4524MDBTEP	THS4524EP	V62/12612-01XE-T

⁽¹⁾ For the most current package and ordering information, see the Package Option Addendum at the end of this document, or visit the device product folder at www.ti.com.

ABSOLUTE MAXIMUM RATINGS(1)

Over operating free-air temperature range (unless otherwise noted).

		THS4524	UNIT	
Supply Vo	oltage, V _{S-} to V _{S+}	5.5	V	
Input/Out	put Voltage, V _I (V _{IN±} , V _{OUT±} , V _{OCM} pins)	$(V_{S-}) - 0.7$ to $(V_{S+}) + 0.7V$	V	
Differentia	al Input Voltage, V _{ID}	1	V	
Output Co	urrent, I _O	100	mA	
Input Cur	rrent, I _I (V _{IN±} , V _{OCM} pins)	10	mA	
Continuo	us Power Dissipation	See Thermal Characteristic Specifications		
Maximum	n Junction Temperature, T _J	+150	°C	
Maximum	Junction Temperature, T _J (continuous operation, long-term reliability)	+125	°C	
Operating	g Free-air Temperature Range, T _A	-55 to 125	°C	
Storage T	Temperature Range, T _{STG}	-65 to +150	°C	
	Human Body Model (HBM)	1300	V	
ESD Rating:	Charge Device Model (CDM)	1000	V	
ramig.	Machine Model (MM)	50	V	

⁽¹⁾ Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

Product Folder Links: THS4524-EP



THERMAL INFORMATION

		THS4524	
	THERMAL METRIC ⁽¹⁾	DBT	UNITS
		38 PINS	
θ_{JA}	Junction-to-ambient thermal resistance (2)	106.9	
θ_{JCtop}	Junction-to-case (top) thermal resistance (3)	59.8	
θ_{JB}	Junction-to-board thermal resistance (4)	66.5	°C/W
ΨЈТ	Junction-to-top characterization parameter ⁽⁵⁾	17.1	30/00
ΨЈВ	Junction-to-board characterization parameter ⁽⁶⁾	66.1	
θ_{JCbot}	Junction-to-case (bottom) thermal resistance (7)	N/A	

- (1) For more information about traditional and new thermal metrics, see the IC Package Thermal Metrics application report, SPRA953.
- (2) The junction-to-ambient thermal resistance under natural convection is obtained in a simulation on a JEDEC-standard, high-K board, as specified in JESD51-7, in an environment described in JESD51-2a.
- (3) The junction-to-case (top) thermal resistance is obtained by simulating a cold plate test on the package top. No specific JEDEC-standard test exists, but a close description can be found in the ANSI SEMI standard G30-88.
- (4) The junction-to-board thermal resistance is obtained by simulating in an environment with a ring cold plate fixture to control the PCB temperature, as described in JESD51-8.
- (5) The junction-to-top characterization parameter, ψ_{JT} , estimates the junction temperature of a device in a real system and is extracted from the simulation data for obtaining θ_{JA} , using a procedure described in JESD51-2a (sections 6 and 7).
- (6) The junction-to-board characterization parameter, ψ_{JB}, estimates the junction temperature of a device in a real system and is extracted from the simulation data for obtaining θ_{JA}, using a procedure described in JESD51-2a (sections 6 and 7).
- (7) The junction-to-case (bottom) thermal resistance is obtained by simulating a cold plate test on the exposed (power) pad. No specific JEDEC standard test exists, but a close description can be found in the ANSI SEMI standard G30-88.

ELECTRICAL CHARACTERISTICS: V_{S+} - V_{S-} = 3.3 V

At V_{S+} = +3.3 V, V_{S-} = 0 V, V_{OCM} = open, V_{OUT} = 2 V_{PP} (differential), R_L = 1 k Ω differential, G = 1 V/V, single-ended input, differential output, and input and output referenced to midsupply, unless otherwise noted.

		T _A	T _A = -55°C to 125°C			TEST
PARAMETER	CONDITIONS	MIN	TYP	MAX	UNIT	LEVEL ⁽¹⁾
AC PERFORMANCE						
Small-Signal Bandwidth	$V_{OUT} = 100 \text{ mV}_{PP}, G = 1$		135		MHz	С
	$V_{OUT} = 100 \text{ mV}_{PP}, G = 2$		49		MHz	С
	$V_{OUT} = 100 \text{ mV}_{PP}, G = 5$		18.6		MHz	С
	$V_{OUT} = 100 \text{ mV}_{PP}, G = 10$		9.3		MHz	С
Gain Bandwidth Product	$V_{OUT} = 100 \text{ mV}_{PP}, G = 10$		93		MHz	С
Large-Signal Bandwidth	$V_{OUT} = 2 V_{PP}, G = 1$		95		MHz	С
Bandwidth for 0.1-dB Flatness	$V_{OUT} = 2 V_{PP}, G = 1$		20		MHz	С
Rising Slew Rate (Differential)	V_{OUT} = 2-V Step, G = 1, R_L = 200 Ω		420		V/µs	С
Falling Slew Rate (Differential)	V_{OUT} = 2-V Step, G = 1, R_L = 200 Ω		460		V/µs	С
Overshoot	V_{OUT} = 2-V Step, G = 1, R_L = 200 Ω		1.2		%	С
Undershoot	V_{OUT} = 2-V Step, G = 1, R_L = 200 Ω		2.1		%	С
Rise Time	V_{OUT} = 2-V Step, G = 1, R_L = 200 Ω		4		ns	С
Fall Time	V_{OUT} = 2-V Step, G = 1, R_L = 200 Ω		3.5		ns	С
Settling Time to 1%	V_{OUT} = 2-V Step, G = 1, R_L = 200 Ω		13		ns	С
Harmonic Distortion						
2nd harmonic	$f = 1 \text{ kHz}, V_{OUT} = 1 V_{RMS}, G = 1^{(2)},$ differential input		-122		dBc	С
	$f = 1 \text{ MHz}, V_{OUT} = 2 V_{PP}, G = 1$		-85		dBc	С
3rd harmonic	$f = 1 \text{ kHz}, V_{OUT} = 1 V_{RMS}, G = 1^{(2)},$ differential input		-141		dBc	С
	$f = 1 \text{ MHz}, V_{OUT} = 2 V_{PP}, G = 1$		-90		dBc	С
Second-Order Intermodulation Distortion	Two-tone, $f_1 = 2$ MHz, $f_2 = 2.2$ MHz, $V_{OUT} = 2$ - V_{PP} envelope		-83		dBc	С

(1) Test levels: (A) 100% tested. (B) Limits set by characterization and simulation. (C) Typical value only for information.

(2) Not directly measureable; calculated using noise gain of 101 as described in the Applications section, Audio Performance.

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At V_{S+} = +3.3 V, V_{S-} = 0 V, V_{OCM} = open, V_{OUT} = 2 V_{PP} (differential), R_L = 1 k Ω differential, G = 1 V/V, single-ended input, differential output, and input and output referenced to midsupply, unless otherwise noted.

		T _A	= -55°C to 1	25°C		TEST
PARAMETER	CONDITIONS	MIN	TYP	MAX	UNIT	LEVEL ⁽¹⁾
Third-Order Intermodulation Distortion	Two-tone, $f_1 = 2$ MHz, $f_2 = 2.2$ MHz, $V_{OUT} = 2-V_{PP}$ envelope		-90		dBc	С
Input Voltage Noise	f > 10 kHz		4.6		nV/√ Hz	С
Input Current Noise	f > 100 kHz		0.6		pA/√Hz	С
Overdrive Recovery Time	Overdrive = ±0.5 V		80		ns	С
Output Balance Error	V _{OUT} = 100 mV, f ≤ 2 MHz (differential input)		-57		dB	С
Closed-Loop Output Impedance	f = 1 MHz (differential)		0.3		Ω	С
Channel-to-Channel Crosstalk	f = 10 kHz, measured differentially		-125		dB	С
DC PERFORMANCE						
Open-Loop Voltage Gain (A _{OL})		80	116		dB	Α
Input-Referred Offset Voltage			±0.5	±7	mV	Α
Input offset voltage drift ⁽³⁾			±2		μV/°C	С
Input Bias Current			0.75	3.8	μΑ	Α
Input bias current drift ⁽³⁾			±1.75		nA/°C	С
Input Offset Current			±0.03	±2.0	uA	Α
Input offset current drift(3)			±0.1		nA/°C	С

⁽³⁾ Input Offset Voltage Drift, Input Bias Current Drift, and Input Offset Current Drift are average values calculated by taking data at -55°C and +125°C, computing the difference, and dividing by 180.

Product Folder Links : THS4524-EP



At V_{S+} = +3.3 V, V_{S-} = 0 V, V_{OCM} = open, V_{OUT} = 2 V_{PP} (differential), R_L = 1 k Ω differential, G = 1 V/V, single-ended input, differential output, and input and output referenced to midsupply, unless otherwise noted.

		TA	= -55°C to 12	25°C		TEST
PARAMETER	CONDITIONS	MIN	TYP	MAX	UNIT	LEVEL ⁽¹⁾
INPUT						
Common-Mode Input Voltage Low			-0.1	0	V	Α
Common-Mode Input Voltage High		1.8	1.9		V	Α
Common-Mode Rejection Ratio (CMRR)		73.8	100		dB	Α
Input Resistance			110 1.5		kΩ∥pF	С
OUTPUT						
Output Voltage Low			0.09	0.2	V	Α
Output Voltage High		2.95	3.05		V	Α
Output Current Drive (for linear operation)	$R_L = 50 \Omega$		±35		mA	С
POWER SUPPLY						
Specified Operating Voltage		2.5		5.5	V	Α
Quiescent Operating Current, per channel		0.85	1.0	1.25	mA	Α
Power-Supply Rejection Ratio (±PSRR)		65	100		dB	Α
POWER DOWN						
Enable Voltage Threshold	Assured on above 2.1 V		1.6	2.1	V	Α
Disable Voltage Threshold	Assured off below 0.7 V	0.7	1.6		V	Α
Disable Pin Bias Current			1		μA	С
Power Down Quiescent Current			10		μA	С
Turn-On Time Delay	Time to V_{OUT} = 90% of final value, V_{IN} = 2 V, R_L = 200 Ω		108		ns	С
Turn-Off Time Delay	Time to V_{OUT} = 10% of original value, V_{IN} = 2 V, R_L = 200 Ω		88		ns	С
V _{OCM} VOLTAGE CONTROL						
Small-Signal Bandwidth			23		MHz	С
Slew Rate			55		V/µs	С
Gain		0.98	0.99	1.021	V/V	Α
Common-Mode Offset Voltage from V _{OCM} Input	Measured at V_{OUT} with V_{OCM} input driven, $V_{OCM} = 1.65 \text{ V} \pm 0.5 \text{ V}$		±2.5	±7	mV	А
Input Bias Current	$V_{OCM} = 1.65 \text{ V} \pm 0.5 \text{ V}$		±5	±8	μΑ	Α
V _{OCM} Voltage Range			0.8 to 2.5		V	С
Input Impedance			72 1.5		kΩ∥pF	С
Default Output Common-Mode Voltage Offset from $(V_{S+}-V_{S-})/2$	Measured at V_{OUT} with V_{OCM} input open		±1.5	±5	mV	Α

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ELECTRICAL CHARACTERISTICS: V_{S+} - V_{S-} = 5 V

At V_{S+} = +5 V, V_{S-} = 0 V, V_{OCM} = open, V_{OUT} = 2 V_{PP} (differential), R_F = 1 k Ω , R_L = 1 k Ω differential, G = 1 V/V, single-ended input, differential output, input and output referenced to midsupply, unless otherwise noted.

		T _A =	-55°C to 12	5°C		TEST
PARAMETER	CONDITIONS	MIN	TYP	MAX	UNIT	LEVEL ⁽¹⁾
AC PERFORMANCE						
Small-Signal Bandwidth	$V_{OUT} = 100 \text{ mV}_{PP}, G = 1$		145		MHz	С
	$V_{OUT} = 100 \text{ mV}_{PP}, G = 2$		50		MHz	С
	$V_{OUT} = 100 \text{ mV}_{PP}, G = 5$		20		MHz	С
	$V_{OUT} = 100 \text{ mV}_{PP}, G = 10$		9.5		MHz	С
Gain Bandwidth Product	$V_{OUT} = 100 \text{ mV}_{PP}, G = 10$		95		MHz	С
Large-Signal Bandwidth	$V_{OUT} = 2 V_{PP}, G = 1$		145		MHz	С
Bandwidth for 0.1-dB Flatness	$V_{OUT} = 2 V_{PP}, G = 1$		30		MHz	С
Rising Slew Rate (Differential)	V_{OUT} = 2-V Step, G = 1, R_L = 200 Ω		490		V/µs	С
Falling Slew Rate (Differential)	V_{OUT} = 2-V Step, G = 1, R_L = 200 Ω		600		V/µs	С
Overshoot	V_{OUT} = 2-V Step, G = 1, R_L = 200 Ω		1		%	С
Undershoot	V_{OUT} = 2-V Step, G = 1, R_L = 200 Ω		2.6		%	С
Rise Time	V_{OUT} = 2-V Step, G = 1, R_L = 200 Ω		3.4		ns	С
Fall Time	V_{OUT} = 2-V Step, G = 1, R_L = 200 Ω		3		ns	С
Settling Time to 1%	V_{OUT} = 2-V Step, G = 1, R_L = 200 Ω		10		ns	С
Harmonic Distortion						
2nd harmonic	$f = 1 \text{ kHz}, V_{OUT} = 1 V_{RMS}, G = 1^{(2)},$ differential input		-122		dBc	С
	$f = 1 \text{ MHz}, V_{OUT} = 2 V_{PP}, G = 1$		-85		dBc	С
3rd harmonic	$f = 1 \text{ kHz}, V_{OUT} = 1 V_{RMS}, G = 1^{(2)},$ differential input		-141		dBc	С
	f = 1 MHz, V _{OUT} = 2 V _{PP} , G = 1		-91		dBc	С
Second-Order Intermodulation Distortion	Two-tone, $f_1 = 2$ MHz, $f_2 = 2.2$ MHz, $V_{OUT} = 2 \cdot V_{PP}$ envelope		-86		dBc	С
Third-Order Intermodulation Distortion	Two-tone, $f_1 = 2$ MHz, $f_2 = 2.2$ MHz, $V_{OUT} = 2 \cdot V_{PP}$ envelope		-93		dBc	С
Input Voltage Noise	f > 10 kHz		4.6		nV/√ Hz	С
Input Current Noise	f > 100 kHz		0.6		pA/√Hz	С
SNR	$V_{OUT} = 5 V_{PP}$, 20 Hz to 22 kHz BW, differential input		114		dBc	С
THD+N	$f = 1 \text{ kHz}$, $V_{OUT} = 5 \text{ V}_{PP}$, 20 Hz to 22 kHz BW, differential input		112		dBc	С
Overdrive Recovery Time	Overdrive = ±0.5 V		75		ns	С
Output Balance Error	V _{OUT} = 100 mV, f < 2 MHz, V _{IN} differential		- 57		dB	С
Closed-Loop Output Impedance	f = 1 MHz (differential)		0.3		Ω	С
Channel-to-Channel Crosstalk	f = 10 kHz, measured differentially		-125		dB	С
DC PERFORMANCE						
Open-Loop Voltage Gain (A _{OL})		83	119		dB	Α
Input-Referred Offset Voltage			±0.5	±8	mV	Α
Input offset voltage drift (3)			±2		μV/°C	С
Input Bias Current			0.9	5.5	μΑ	Α
Input bias current drift (3)			±1.8		nA/°C	С

⁽¹⁾ Test levels: (A) 100% tested. (B) Limits set by characterization and simulation. (C) Typical value only for information.

⁽²⁾ Not directly measureable; calculated using noise gain of 101 as described in the Applications section, Audio Performance.

⁽³⁾ Input Offset Voltage Drift, Input Bias Current Drift, and Input Offset Current Drift are average values calculated by taking data at -55°C and +125°C, computing the difference, and dividing by 180.

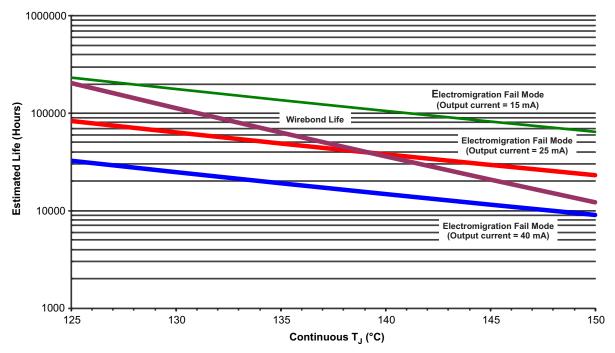


At V_{S+} = +5 V, V_{S-} = 0 V, V_{OCM} = open, V_{OUT} = 2 V_{PP} (differential), R_F = 1 k Ω , R_L = 1 k Ω differential, G = 1 V/V, single-ended input, differential output, input and output referenced to midsupply, unless otherwise noted.

		T _A =	-55°C to 12	5°C		TEST
PARAMETER	CONDITIONS	MIN	TYP	MAX	UNIT	LEVEL ⁽¹⁾
Input Offset Current			±0.03	±1.7	uA	А
Input offset current drift (4)			±0.1		nA/°C	С
INPUT						
Common-Mode Input Voltage Low			-0.1	0	V	Α
Common-Mode Input Voltage High		3.5	3.6		V	Α
Common-Mode Rejection Ratio (CMRR)		80	102		dB	Α
Input Impedance			100 0.7		kΩ∥pF	С
OUTPUT						
Output Voltage Low			0.115	0.2	V	Α
Output Voltage High		4.65	4.7		V	Α
Output Current Drive (for linear operation)	$R_L = 50 \Omega$		±55		mA	С
POWER SUPPLY						
Specified Operating Voltage		2.5		5.5	V	Α
Quiescent Operating Current, per channel		0.9	1.15	1.4	mA	Α
Power-Supply Rejection Ratio (±PSRR)		62	100		dB	Α
POWER DOWN						
Enable Voltage Threshold	Ensured on above 2.1 V		1.6	2.1	V	Α
Disable Voltage Threshold	Ensured off below 0.7 V	0.7	1.6		V	Α
Disable Pin Bias Current			1		μΑ	С
Power Down Quiescent Current			20		μΑ	С
Turn-On Time Delay	Time to V_{OUT} = 90% of final value, V_{IN} = 2 V, R_L = 200 Ω		70		ns	С
Turn-Off Time Delay	Time to V_{OUT} = 10% of original value, V_{IN} = 2 V, R_L = 200 Ω		60		ns	С
V _{OCM} VOLTAGE CONTROL						
Small-Signal Bandwidth			23		MHz	С
Slew Rate			55		V/µs	С
Gain		0.98	0.99	1.021	V/V	Α
Common-Mode Offset Voltage from $V_{\rm OCM}$ Input	Measured at V_{OUT} with V_{OCM} input driven, $V_{OCM} = 2.5 V \pm 1 V$		±5	±12.5	mV	Α
Input Bias Current	$V_{OCM} = 2.5V \pm 1 V$		±20	±25	μΑ	Α
V _{OCM} Voltage Range			0.8 to 4.2		V	С
Input Impedance			46 1.5		kΩ∥pF	С
Default Output Common-Mode Voltage Offset from $(V_{S+}-V_{S-})/2$	Measured at V _{OUT} with V _{OCM} input open		±1	±8	mV	А

⁽⁴⁾ Input Offset Voltage Drift, Input Bias Current Drift, and Input Offset Current Drift are average values calculated by taking data at -55°C and +125°C, computing the difference, and dividing by 180.





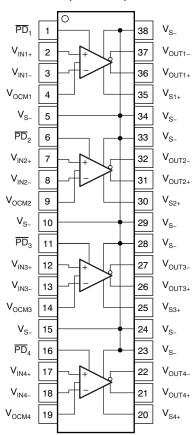
- A. See datasheet for absolute maximum and minimum recommended operating conditions.
- B. Silicon operating life design goal is 10 years at 105°C junction temperature (does not include package interconnect life).

Figure 1. Electromigration Fail Mode/Wirebond Life Derating Chart



DEVICE INFORMATION

TSSOP-38 (DBT PACKAGE) (TOP VIEW)





TERMINAL FUNCTIONS

TSSC	TSSOP-38					
PIN NO.	NAME	DESCRIPTION				
1	PD ₁	Power down 1. \overline{PD} = logic low puts channel into low-power mode. \overline{PD} = logic high or open for normal operation.				
2	V _{IN1+}	Noninverting amplifier 1 input				
3	V _{IN1} _	Inverting amplifier 1 input				
4	V_{OCM1}	Common-mode voltage input 1				
5	V _{S-}	Negative power-supply input. Note that V _S is tied together on multi-channel devices.				
6	PD ₂	Power down 2. \overline{PD} = logic low puts channel into low-power mode. \overline{PD} = logic high or open for normal operation.				
7	V_{IN2+}	Noninverting amplifier 2 input				
8	V_{IN2-}	Inverting amplifier 2 input				
9	V_{OCM2}	Common-mode voltage input 2				
10	V_{S-}	Negative power-supply input. Note that V_{S-} is tied together on multi-channel devices.				
11	PD ₃	Power down 3. \overline{PD} = logic low puts channel into low-power mode. \overline{PD} = logic high or open for normal operation.				
12	V _{IN3+}	Noninverting amplifier 3 input				
13	V _{IN3-}	Inverting amplifier 3 input				
14	V_{OCM3}	Common-mode voltage input 3				
15	V_{S-}	Negative power-supply input. Note that V_{S-} is tied together on multi-channel devices.				
16	PD ₄	Power down 4. \overline{PD} = logic low puts channel into low-power mode. \overline{PD} = logic high or open for normal operation.				
17	V_{IN4+}	Noninverting amplifier 4 input				
18	V_{IN4-}	Inverting amplifier 4 input				
19	V_{OCM4}	Common-mode voltage input 4				
20	V_{S4+}	Amplifier 4 positive power-supply input				
21	V_{OUT4+}	Noninverting amplifier 4 output				
22	V_{OUT4-}	Inverting amplifier 4 output				
23	V_{S-}	Negative power-supply input. Note that V_{S-} is tied together on multi-channel devices.				
24	V_{S-}	Negative power-supply input. Note that V_{S-} is tied together on multi-channel devices.				
25	V_{S3+}	Amplifier 3 positive power-supply input				
26	V _{OUT3+}	Noninverting amplifier3 output				
27	V _{OUT3-}	Inverting amplifier3 output				
28	V_{S-}	Negative power-supply input. Note that V_{S-} is tied together on multi-channel devices.				
29	V_{S-}	Negative power-supply input. Note that V_{S-} is tied together on multi-channel devices.				
30	V_{S2+}	Amplifier 2 positive power-supply input				
31	V_{OUT2+}	Noninverting amplifier 2 output				
32	V_{OUT2-}	Inverting amplifier 2 output				
33	V_{S-}	Negative power-supply input. Note that V_{S-} is tied together on multi-channel devices.				
34	V_{S-}	Negative power-supply input. Note that V_{S-} is tied together on multi-channel devices.				
35	V _{S1+}	Amplifier 1 positive power-supply input				
36	V _{OUT1+}	Noninverting amplifier 1 output				
37	V _{OUT1-}	Inverting amplifier 1 output				
38	V_{S-}	Negative power-supply input. Note that V_{S-} is tied together on multi-channel devices.				



TYPICAL CHARACTERISTICS

Table of Graphs: $V_{S+} - V_{S-} = 3.3 \text{ V}$

TITLE	FIGURE
Small-Signal Frequency Response	Figure 2
Large-Signal Frequency Response	Figure 3
Large- and Small-Signal Pulse Response	Figure 4
Slew Rate vs V _{OUT} Step	Figure 5
Overdrive Recovery	Figure 6
10-kHz Output Spectrum on AP Analyzer	Figure 7
Harmonic Distortion vs Frequency	Figure 8
Harmonic Distortion vs Output Voltage at 1 MHz	Figure 9
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Output Balance Error vs Frequency	Figure 24
V _{OCM} Small-Signal Frequency Response	Figure 25
V _{OCM} Large-Signal Frequency Response	Figure 26
V _{OCM} Input Impedance vs Frequency	Figure 27

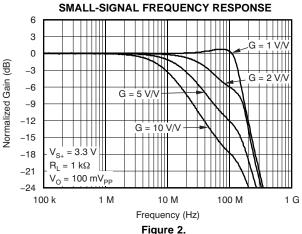


Table of Graphs: $V_{S+} - V_{S-} = 5 \text{ V}$

1 usio 0 1 usio 1 v 5+ v 5 0 v				
TITLE	FIGURE			
Small-Signal Frequency Response	Figure 28			
Large-Signal Frequency Response	Figure 29			
Large- and Small-Signal Pulse Response	Figure 30			
Slew Rate vs V _{OUT} Step	Figure 31			
Overdrive Recovery	Figure 32			
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Output Balance Error vs Frequency	Figure 50			
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V _{OCM} Large-Signal Frequency Response	Figure 52			
V _{OCM} Input Impedance vs Frequency	Figure 53			



At V_{S+} = +3.3 V, V_{S-} = 0 V, V_{OCM} = open, V_{OUT} = 2 V_{PP} (differential), R_L = 1 $k\Omega$ differential, G = 1 V/V, single-ended input, differential output, and input and output referenced to midsupply, unless otherwise noted.



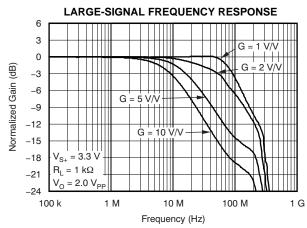


Figure 3.

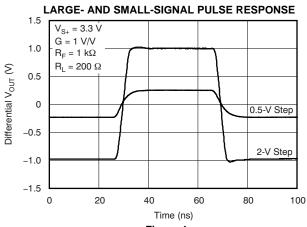
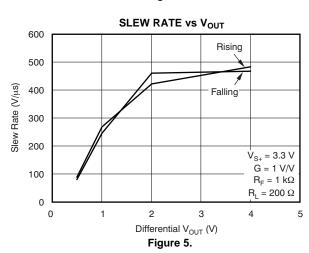
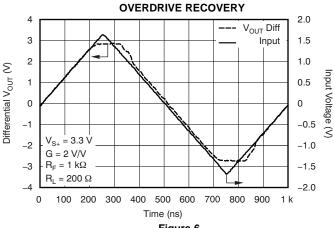


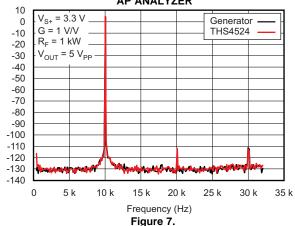
Figure 4.



10-kHz OUTPUT SPECTRUM ON AP ANALYZER





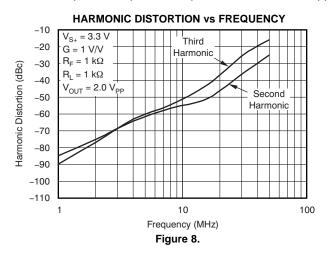


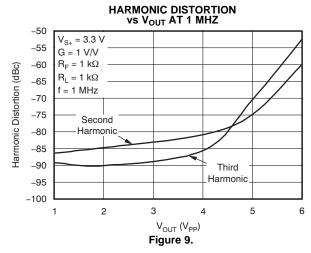
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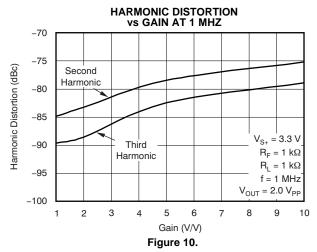
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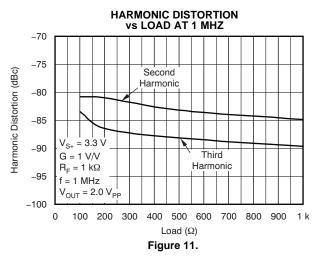


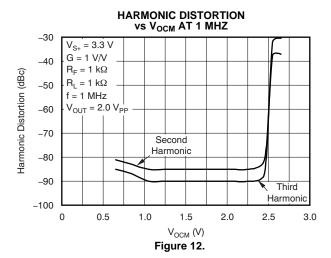
At V_{S+} = +3.3 V, V_{S-} = 0 V, V_{OCM} = open, V_{OUT} = 2 V_{PP} (differential), R_L = 1 k Ω differential, G = 1 V/V, single-ended input, differential output, and input and output referenced to midsupply, unless otherwise noted.

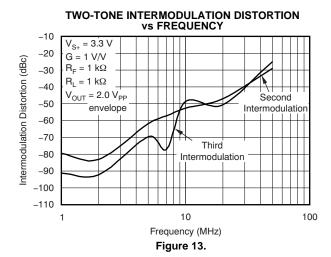






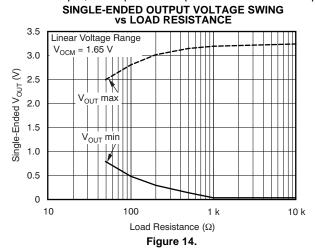




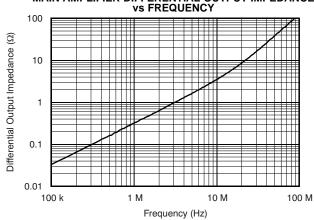


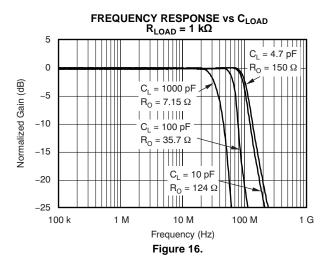


At V_{S+} = +3.3 V, V_{S-} = 0 V, V_{OCM} = open, V_{OUT} = 2 V_{PP} (differential), R_L = 1 k Ω differential, G = 1 V/V, single-ended input, differential output, and input and output referenced to midsupply, unless otherwise noted.

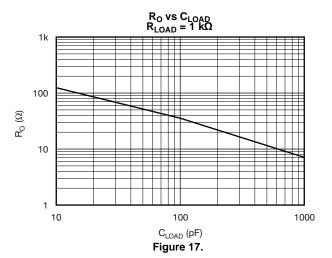


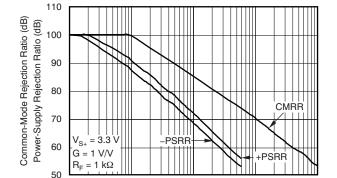
MAIN AMPLIFIER DIFFERENTIAL OUTPUT IMPEDANCE vs FREQUENCY











REJECTION RATIO vs FREQUENCY

CROSSTALK (MEASURED DIFFERENTIALLY)

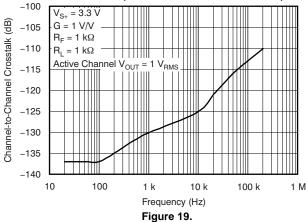


Figure 18.

10 M

1 M

Frequency (Hz)

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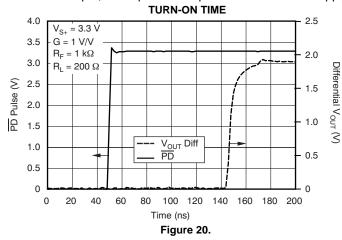
100 k

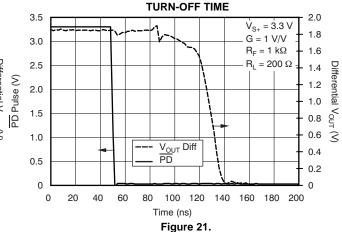
10 k

100 M

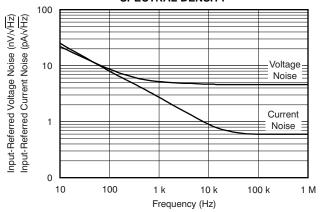


At V_{S+} = +3.3 V, V_{S-} = 0 V, V_{OCM} = open, V_{OUT} = 2 V_{PP} (differential), R_L = 1 k Ω differential, G = 1 V/V, single-ended input, differential output, and input and output referenced to midsupply, unless otherwise noted.





INPUT-REFERRED VOLTAGE AND CURRENT NOISE SPECTRAL DENSITY



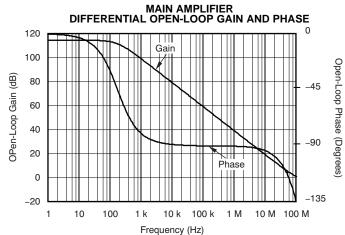
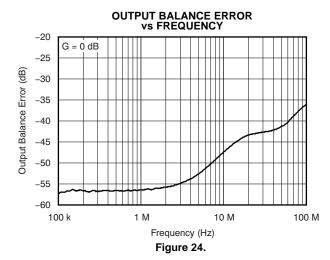


Figure 22.



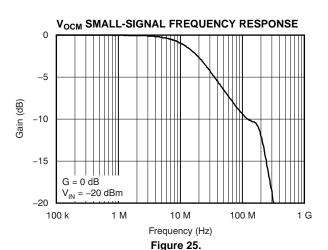
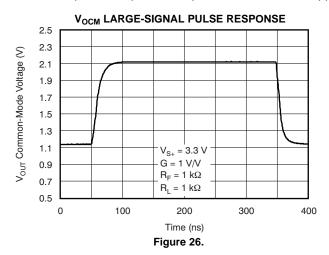


Figure 23.



At V_{S+} = +3.3 V, V_{S-} = 0 V, V_{OCM} = open, V_{OUT} = 2 V_{PP} (differential), R_L = 1 k Ω differential, G = 1 V/V, single-ended input, differential output, and input and output referenced to midsupply, unless otherwise noted.



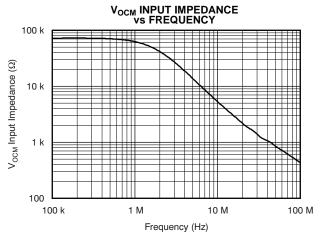


Figure 27.

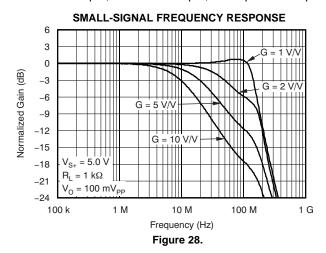
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TYPICAL CHARACTERISTICS: 5 V

At V_{S+} = +5 V, V_{S-} = 0 V, V_{OCM} = open, V_{OUT} = 2 V_{PP} (differential), R_F = 1 k Ω , R_L = 1 k Ω differential, G = 1 V/V, single-ended input, differential output, and input and output referenced to midsupply, unless otherwise noted.



6 3 G = 1 V/V0 Normalized Gain (dB) -3 G = 2 V/-6 G = 5 V/V-9 -12 G = 10 V/V-15 = 5.0 V -18 $R_L = 1 \text{ k}\Omega$ -21 = 2.0 V_{PP} -24 100 M 100 k 1 M 10 M 1 G Frequency (Hz) Figure 29.

LARGE-SIGNAL FREQUENCY RESPONSE

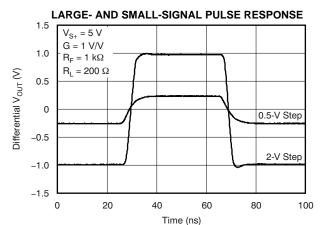
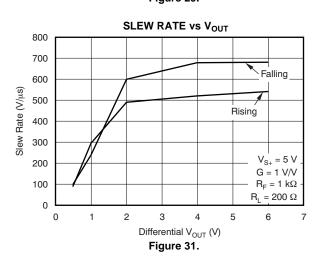
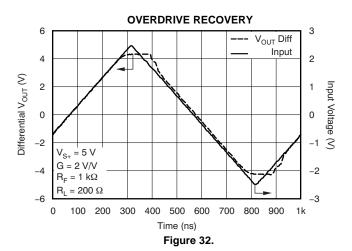
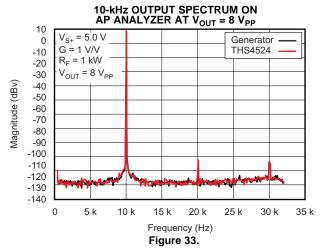


Figure 30.



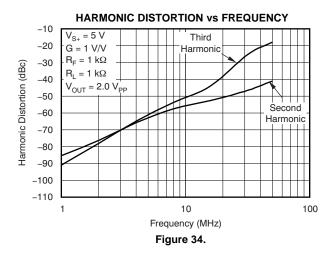


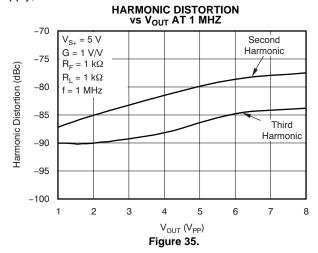


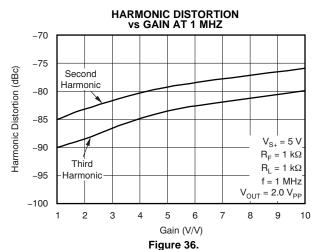
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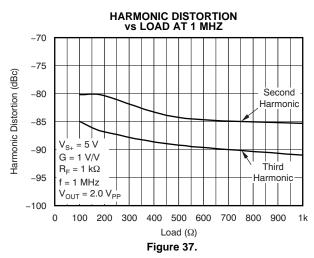


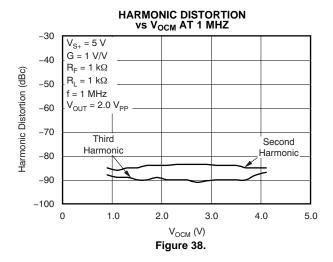
At V_{S+} = +5 V, V_{S-} = 0 V, V_{OCM} = open, V_{OUT} = 2 V_{PP} (differential), R_F = 1 k Ω , R_L = 1 k Ω differential, G = 1 V/V, single-ended input, differential output, and input and output referenced to midsupply, unless otherwise noted.

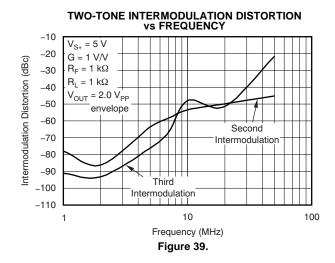










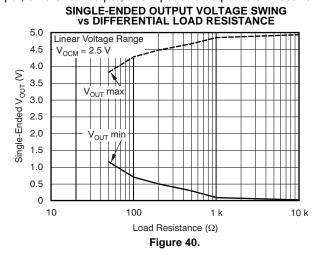


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At V_{S+} = +5 V, V_{S-} = 0 V, V_{OCM} = open, V_{OUT} = 2 V_{PP} (differential), R_F = 1 k Ω , R_L = 1 k Ω differential, G = 1 V/V, single-ended input, differential output, and input and output referenced to midsupply, unless otherwise noted.





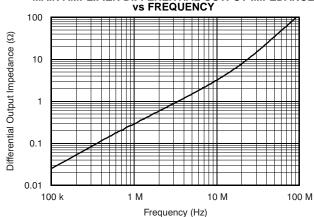
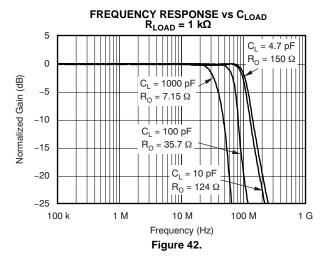
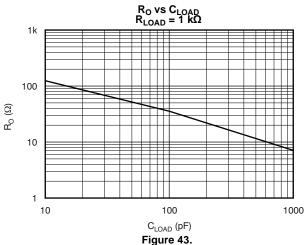
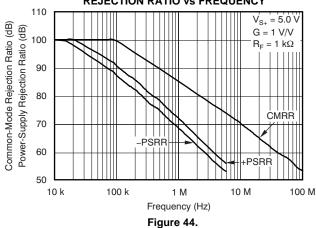


Figure 41.





REJECTION RATIO vs FREQUENCY



CROSSTALK (MEASURED DIFFERENTIALLY)

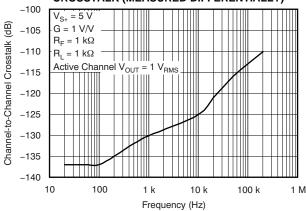
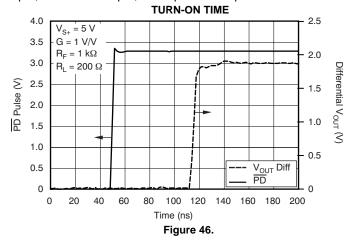
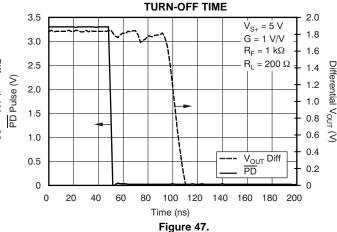


Figure 45.



At V_{S+} = +5 V, V_{S-} = 0 V, V_{OCM} = open, V_{OUT} = 2 V_{PP} (differential), R_F = 1 k Ω , R_L = 1 k Ω differential, G = 1 V/V, single-ended input, differential output, and input and output referenced to midsupply, unless otherwise noted.





INPUT-REFERRED VOLTAGE AND CURRENT NOISE SPECTRAL DENSITY

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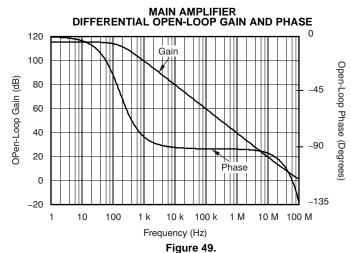
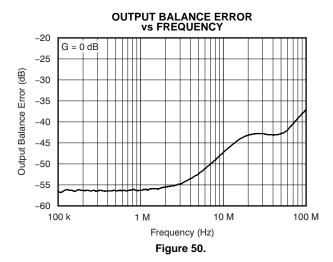


Figure 48.



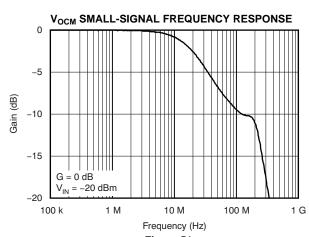
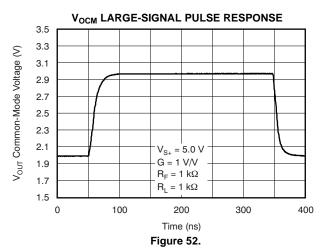


Figure 51.



At V_{S+} = +5 V, V_{S-} = 0 V, V_{OCM} = open, V_{OUT} = 2 V_{PP} (differential), R_F = 1 k Ω , R_L = 1 k Ω differential, G = 1 V/V, single-ended input, differential output, and input and output referenced to midsupply, unless otherwise noted.



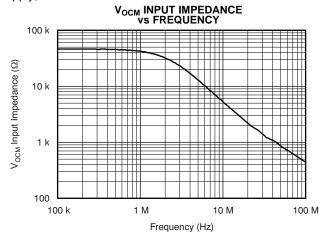


Figure 53.

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TEST CIRCUITS

Overview

The THS4524 is tested with the test circuits shown in this section; all circuits are built using the available THS4524 evaluation module (EVM). For simplicity, power-supply decoupling is not shown; see the layout in the Applications section for recommendations. Depending on the test conditions, component values change in accordance with Table 1 and Table 2, or as otherwise noted. In some cases the signal generators used are ac-coupled and in others they dc-coupled $50-\Omega$ sources. To balance the amplifier when ac-coupled, a 0.22- μF capacitor and 49.9- Ω resistor to ground are inserted across RIT on the alternate input; when dc-coupled, only the $49.9-\Omega$ resistor to ground is added across R_{IT}. A split power supply is used to ease the interface to common test equipment, but the amplifier can be operated in a single-supply configuration as described in the Applications section with no impact on performance. Also, for most of the tests, except as noted, the devices are tested with single-ended inputs and a transformer on the output to convert the differential output to single-ended because common lab test equipment has single-ended inputs and outputs. Similar or better performance can be expected with differential inputs and outputs.

As a result of the voltage divider on the output formed by the load component values, the amplifier output is attenuated. The *Atten* column in Table 2 shows the attenuation expected from the resistor divider. When using a transformer at the output (as shown in Figure 55), the signal sees slightly more loss because of transformer and line loss; these numbers are approximate.

Table 1. Gain Component Values for Single-Ended Input⁽¹⁾

Gain	R _F	R_{G}	R _{IT}
1 V/V	1 kΩ	1 kΩ	52.3 Ω
2 V/V	1 kΩ	487 Ω	53.6 Ω
5 V/V	1 kΩ	187 Ω	59.0 Ω
10 V/V	1 kΩ	86.6 Ω	69.8 Ω

1. Gain setting includes $50-\Omega$ source impedance. Components are chosen to achieve gain and $50-\Omega$

 Ω input termination.

Table 2. Load Component Values For 1:1
Differential to Single-Ended Output Transformer⁽¹⁾

R _L	R _o	R _{OT}	Atten
100 Ω	24.9 Ω	Open	6 dB
200 Ω	86.6 Ω	69.8 Ω	16.8 dB
499 Ω	237 Ω	56.2 Ω	25.5 dB
1 kΩ	487 Ω	52.3 Ω	31.8 dB

1. Total load includes $50-\Omega$ termination by the test equipment. Components are chosen to achieve load and $50-\Omega$ line termination through a 1:1 transformer.

Frequency Response

The circuit shown in Figure 54 is used to measure the frequency response of the circuit.

An HP network analyzer is used as the signal source and the measurement device. The output impedance of the HP network analyzer is is dc-coupled and is 50 $\Omega.\ R_{IT}$ and R_G are chosen to impedance-match to 50 Ω and maintain the proper gain. To balance the amplifier, a $49.9\text{-}\Omega$ resistor to ground is inserted across R_{IT} on the alternate input.

The output is probed using a Tektronix high-impedance differential probe across the 953- Ω resistor and referred to the amplifier output by adding back the 0.42-dB because of the voltage divider on the output.

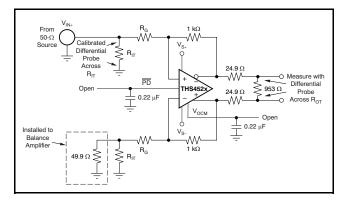


Figure 54. Frequency Response Test Circuit



Distortion

The circuit shown in Figure 55 is used to measure harmonic and intermodulation distortion of the amplifier.

An HP signal generator is used as the signal source and the output is measured with a Rhode and Schwarz spectrum analyzer. The output impedance of the HP signal generator is ac-coupled and is 50 Ω . R_{IT} and R_{G} are chosen to impedance match to 50 Ω and maintain the proper gain. To balance the amplifier, a 0.22- μF capacitor and 49.9- Ω resistor to ground are inserted across R_{IT} on the alternate input.

A low-pass filter is inserted in series with the input to reduce harmonics generated at the signal source. The level of the fundamental is measured and then a high-pass filter is inserted at the output to reduce the fundamental so it does not generate distortion in the input of the spectrum analyzer.

The transformer used in the output to convert the signal from differential to single-ended is an ADT1-1WT. It limits the frequency response of the circuit so that measurements cannot be made below approximately 1 MHz.

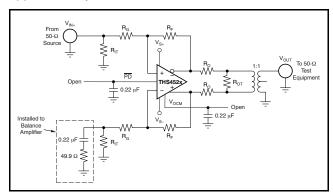


Figure 55. Distortion Test Circuit

Slew Rate, Transient Response, Settling Time, Output Impedance, Overdrive, Output Voltage, and Turn-On/Turn-Off Time

The circuit shown in Figure 56 is used to measure slew rate, transient response, settling time, output impedance, overdrive recovery, output voltage swing, and ampliifer turn-on/turn-off time. Turn-on and turn-off time are measured with the same circuit modified for $50\text{-}\Omega$ input impedance on the \overline{PD} input by replacing the $0.22\text{-}\mu\text{F}$ capacitor with a $49.9\text{-}\Omega$ resistor. For output impedance, the signal is injected at V_{OUT} with V_{IN} open; the drop across the 2x $49.9\text{-}\Omega$ resistors is then used to calculate the impedance seen looking into the amplifier output.

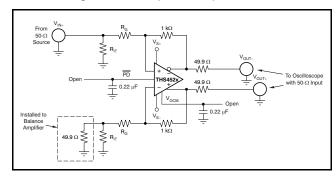


Figure 56. Slew Rate, Transient Response, Settling Time, Output Impedance, Overdrive Recovery, V_{OUT} Swing, and Turn-On/Turn-Off Test Circuit



Common-Mode and Power-Supply Rejection

The circuit shown in Figure 57 is used to measure the CMRR. The signal from the network analyzer is applied common-mode to the input. Figure 58 is used to measure the PSRR of V_{S+} and V_{S-} . The power supply under test is applied to the network analyzer dc offset input. For both CMRR and PSRR, the output is probed using a Tektronix high-impedance differential probe across the 953- Ω resistor and referred to the amplifier output by adding back the 0.42-dB as a result of the voltage divider on the output. For these tests, the resistors are matched for best results.

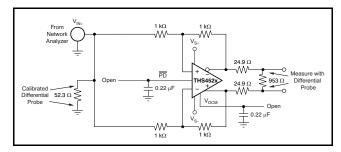


Figure 57. CMRR Test Circuit

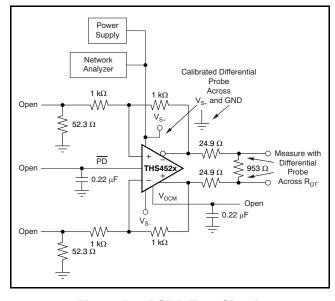


Figure 58. PSRR Test Circuit

V_{ocm} Input

The circuit illustrated in Figure 59 is used to measure the frequency response and input impedance of the V_{OCM} input. Frequency response is measured using a Tektronix high-impedance differential probe, with $R_{CM}=0~\Omega$ at the common point of V_{OUT+} and V_{OUT-} , formed at the summing junction of the two matched 499- Ω resistors, with respect to ground. The input impedance is measured using a Tektronix high-impedance differential probe at the V_{OCM} input with $R_{CM}=10~k\Omega$ and the drop across the $10\text{-}k\Omega$ resistor is used to calculate the impedance seen looking into the amplifier V_{OCM} input.

The circuit shown in Figure 60 measures the transient response and slew rate of the V_{OCM} input. A 1-V step input is applied to the V_{OCM} input and the output is measured using a $50-\Omega$ oscilloscope input referenced back to the amplifier output.

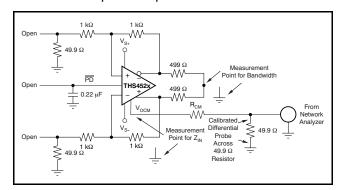


Figure 59. V_{OCM} Input Test Circuit

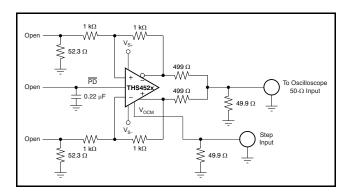


Figure 60. V_{OCM} Transient Response and Slew Rate Test Circuit



APPLICATION INFORMATION

The following circuits show application information for the THS4524. For simplicity, power-supply decoupling capacitors are not shown in these diagrams: **EVM** see the and Layout Recommendations section for suggested guidelines. For more details on the use and operation of fully differential op amps, refer to the Application Report Fully-Differential Amplifiers (SLOA054), available for download from the TI web site at www.ti.com.

Differential Input to Differential Output Amplifier

The THS4524 is a fully-differential operational amplifier that can be used to amplify differential input signals to differential output signals. Figure 61 shows a basic block diagram of the circuit (V_{OCM} and \overline{PD} inputs not shown). The gain of the circuit is set by R_F divided by R_G .

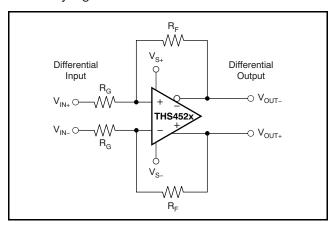


Figure 61. Differential Input to Differential Output Amplifier

Single-Ended Input to Differential Output Amplifier

The THS4524 can also amplify and convert single-ended input signals to differential output signals. Figure 62 illustrates a basic block diagram of the circuit (V_{OCM} and \overline{PD} inputs not shown). The gain of the circuit is again set by R_F divided by R_G .

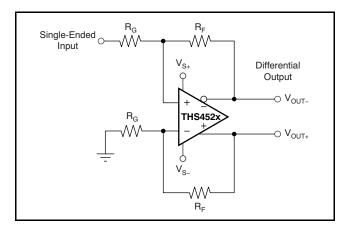


Figure 62. Single-Ended Input to Differential Output Amplifier

Input Common-Mode Voltage Range

The input common-mode voltage of a fully-differential op amp is the voltage at the + and – input pins of the device.

It is important to not violate the input common-mode voltage range (V_{ICR}) of the op amp. Assuming the op amp is in linear operation, the voltage across the input pins is only a few millivolts at most. Therefore, finding the voltage at one input pin determines the input common-mode voltage of the op amp.

Treating the negative input as a summing node, the voltage is given by Equation 1:

$$\left[V_{OUT+} \times \frac{R_G}{R_G + R_F}\right] + \left[V_{IN-} \times \frac{R_F}{R_G + R_F}\right] \tag{1}$$

To determine the V_{ICR} of the op amp, the voltage at the negative input is evaluated at the extremes of V_{OUT+} . As the gain of the op amp increases, the input common-mode voltage becomes closer and closer to the input common-mode voltage of the source.

Setting the Output Common-Mode Voltage

The output common-model voltage is set by the voltage at the $V_{\rm OCM}$ pin. The internal common-mode control circuit maintains the output common-mode voltage within 5-mV offset (typ) from the set voltage. If left unconnected, the common-mode set point is set to midsupply by internal circuitry, which may be overdriven from an external source.

Figure 63 represents the V_{OCM} input. The internal V_{OCM} circuit has typically 23 MHz of -3 dB bandwidth, which is required for best performance, but it is intended to be a dc bias input pin. A 0.22- μF bypass capacitor is recommended on this pin to reduce noise. The external current required to overdrive the internal resistor divider is given approximately by the formula in Equation 2:

$$I_{\text{EXT}} = \ \frac{2V_{\text{OCM}} - (V_{\text{S+}} - V_{\text{S-}})}{50 \ k\Omega}$$

where:

• V_{OCM} is the voltage applied to the V_{OCM} pin (2)

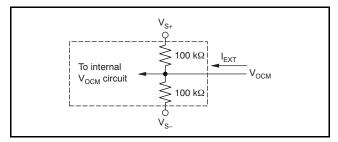


Figure 63. V_{OCM} Input Circuit

Typical Performance Variation with Supply Voltage

The THS4524 provides excellent performance across the specified power-supply range of 2.5 V to 5.5 V with only minor variations. The input and output voltage compliance ranges track with the power supply in nearly a 1:1 correlation. Other changes can be observed in slew rate, output current drive, open-loop gain, bandwidth, and distortion. Table 3 shows the typical variation to be expected in these key performance parameters.

Single-Supply Operation

To facilitate testing with common lab equipment, the THS4524EVM allows for split-supply operation; most of the characterization data presented in this data sheet is measured using split-supply power inputs. The device can easily be used with a single-supply power input without degrading performance.

Figure 64 shows a dc-coupled single-supply circuit with single-ended inputs. This circuit can also be applied to differential input sources.

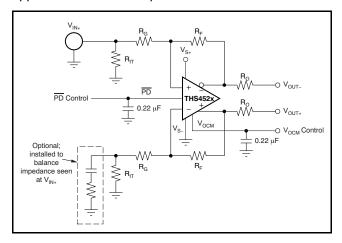


Figure 64. THS4524 DC-Coupled Single-Supply with Single-Ended Inputs

The input common-mode voltage range of the THS4524 is designed to include the negative supply voltage. in the circuit shown in Figure 64, the signal source is referenced to ground. $V_{\rm OCM}$ is set by an external control source or, if left unconnected, the internal circuit defaults to midsupply. Together with the input impedance of the amplifier circuit, $R_{\rm IT}$ provides input termination, which is also referenced to ground.

Note that R_{IT} and optional matching components are added to the alternate input to balance the impedance at signal input.

Table 3. Typical Performance Variation versus Power-Supply Voltage

PARAMETER	V _S = 5 V	V _S = 3.3 V	V _S = 2.5 V		
-3-dB Small-signal bandwidth	145 MHz	135 MHz	125 MHz		
Slew rate (2-V step)	490 V/µs	490 V/μs 420 V/μs			
Harmonic distortion at 1 MHz, 2 V_{PP} , R_L = 1 $k\Omega$					
Second harmonic	-85 dBc	-85 dBc	-84 dBc		
Third harmonic	-91 dBc	-90 dBc	-88 dBc		
Open-loop gain	119 dB	116 dB	115 dB		
Linear output current drive	55 mA	35 mA	24 mA		



Low-Power Applications and the Effects of Resistor Values on Bandwidth

For low-power operation, it may be necessary to increase the gain setting resistors values to limit current consumption and not load the source. Using larger value resistors lowers the bandwidth of the THS4524 as a result of the interactions between the resistors, the device parasitic capacitance, and printed circuit board (PCB) parasitic capacitance. Figure 65 shows the small-signal frequency response with 1-k Ω , 10-k Ω , and 100-k Ω resistors for R_F , R_G , and R_L (impedance is assumed to typically increase for all three resistors in low-power applications).

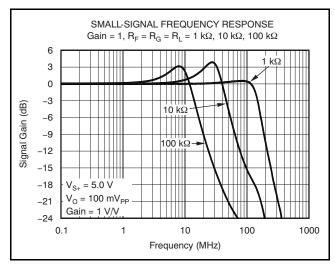


Figure 65. THS4524 Frequency Response with Various Gain Setting and Load Resistor Values

Frequency Response Variation due to Package Options

Users can see variations in the small-signal ($V_{OUT} = 100 \text{ mV}_{PP}$) frequency response between the available package options for the THS452x family as a result of parasitic elements associated with each package and board layout changes. Figure 66 shows the variance measured in the lab; this variance is to be expected even when using a good layout.

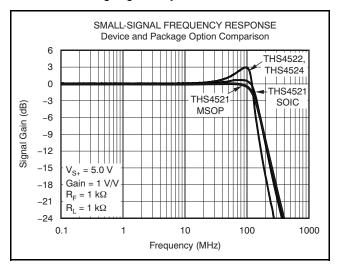


Figure 66. Small-Signal Frequency Response: Package Variations

TEXAS INSTRUMENTS

Driving Capacitive Loads

The THS4524 is designed for a nominal capacitive load of 1 pF on each output to ground. When driving capacitive loads greater than 1 pF, it is recommended to use small resistors (R_O) in series with the output, placed as close to the device as possible. Without R_O, capacitance on the output interacts with the output impedance of the amplifier and causes phase shift in the loop gain of the amplifier that reduces the phase margin. This reduction in phase margin results in frequency response peaking; overshoot. undershoot, and/or ringing when a step or squarewave signal is applied; and may lead to instability or oscillation. Inserting R_O isolates the phase shift from the loop gain path and restores the phase margin, but it also limits bandwidth. Figure 67 shows the recommended values of Ro versus capacitive loads (CL), and Figure 68 shows an illustration of the frequency response with various values.

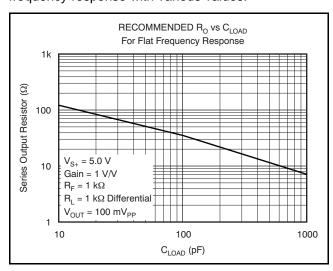


Figure 67. Recommended Series Output Resistor versus Capacitive Load for Flat Frequency Response, with $R_{LOAD} = 1 \text{ k}\Omega$

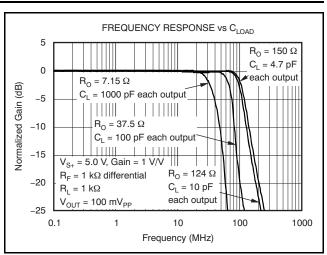


Figure 68. Frequency Response for Various R_O and C_L Values, with R_{LOAD} = 1 k Ω

Audio Performance

The THS4524 provides excellent audio performance with very low quiescent power. To show performance in the audio band, the device was tested with a SYS-2722 audio analyzer from Audio Precision. THD+N and FFT tests were performed at 1-V_{RMS} output voltage. Performance is the same on both 3.3-V and 5-V supplies. Figure 69 shows the test circuit used; see Figure 70 and Figure 71 for the performance of the analyzer using internal loopback mode (generator) together with the THS4524.

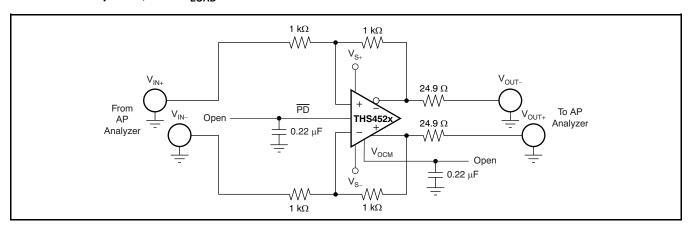


Figure 69. THS4524 AP Analyzer Test Circuit



Note that the harmonic distortion performance is very close to the same with and without the device meaning the THS4524 performance is actually much better than can be directly measured by this meathod. The actual device performance can be estimated by placing the device in a large noise gain and using the reduction in loop gain correction. The THS4524 is placed in a noise gain of 101 by adding a 10-Ω resistor directly across the input terminals of the circuit shown in Figure 69. This test was performed using the AP instrument as both the signal source and the analyzer. The second-order harmonic distortion at 1 kHz is estimated to be -122 dBc with $V_O = 1V_{RMS}$; third-order harmonic distortion is estimated to be -141 dBc. The third-order harmonic distortion result matches exactly with design simulations, but the second-order harmonic distortion is about 10 dB worse. This result is not unexpected second-order harmonic distortion because performance with a differential signal depends heavily on cancellation as a result of the differential nature of the signal, which depends on board layout, bypass capacitors, external cabling, and so forth. Note that the circuit of Figure 69 is also used to measure crosstalk between channels.

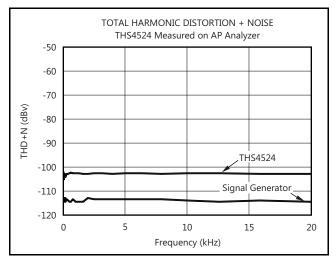


Figure 70. THS4524 1-V_{RMS} 20-Hz to 20-kHz THD+N

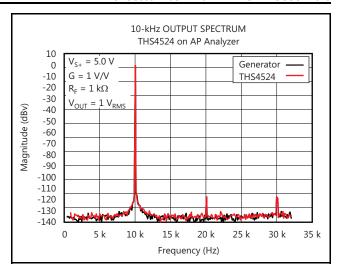


Figure 71. THS4524 1-V_{RMS} 10-kHz FFT Plot

The THS4524 shows even better THD+N performance when driving higher amplitude output, such as 5 V_{PP} that is more typical when driving an ADC. To show performance with an extended frequency range, higher gain, and higher amplitude, the device was tested with 5 V_{PP} up to 80 kHz with the AP. Figure 72 shows the resulting THD+N graph with no weighting.

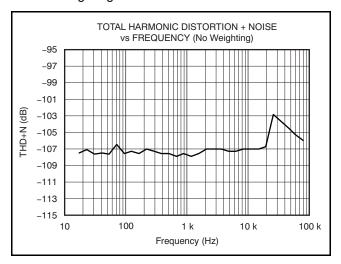


Figure 72. THD+N (No Weighting) on AP, 80-kHz Bandwidth at G = 1 with $5-V_{PP}$ Output

Audio On/Off Pop Performance

The THS4524 was tested to show on and off pop performance by connecting a speaker between the differential outputs and switching the power supply on and off, and also by using the PD function of the THS4524. Testing was done with and without tones. During these tests, no audible pop could be heard.

With no tone input, Figure 73 shows the pop performance when switching power on to the THS4524 and Figure 74 shows the device performance when turning the power off. The transients during power on and off illustrate that no audible pop should be heard

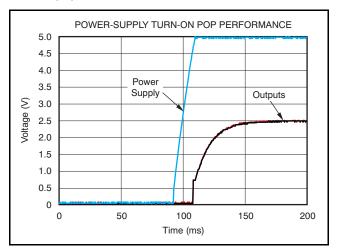


Figure 73. THS4524 Power-Supply Turn-On Pop Performance

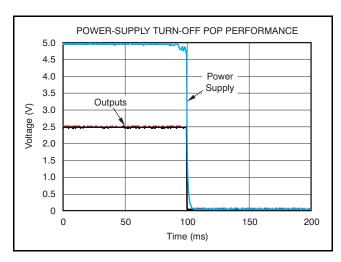


Figure 74. THS4524 Power-Supply Turn-Off Pop Performance

With no tone input, Figure 75 shows the pop performance using the PD pin to enable the THS4524, and Figure 76 shows performance using the PD pin to disable the device. Again, the transients during power on and off show that no audible pop should be heard. It should also be noted that the turn on/off times are faster using the PD pin technique.

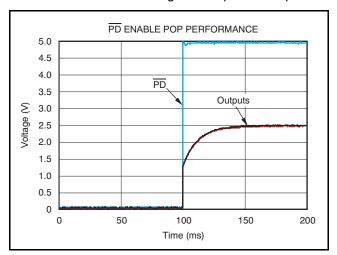


Figure 75. THS4524 PD Pin Enable Pop Performance

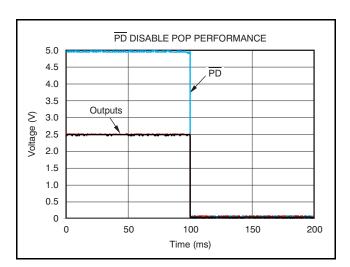


Figure 76. THS4524 PD Pin Disable Pop Performance

The power on/off pop performance of the THS4524, whether by switching the power supply or when using the power-down function built into the chip, shows that no special design should be required to prevent an audible pop.



Audio ADC Driver Performance: THS4524 and PCM4204 Combined Performance

To show achievable performance with a high-performance audio ADC, the THS4524 is tested as the drive amplifier for the PCM4204. The PCM4204 is a high-performance, four-channel ADC designed for professional and broadcast audio applications. The PCM4204 architecture uses a 1-bit delta-sigma $(\Delta\Sigma)$ modulator per channel that incorporates an advanced dither scheme for improved dynamic performance, and supports PCM output data. The PCM4204 provides a flexible serial port interface and many other advanced features. Refer to the PCM4204 product data sheet for more information.

The PCM4204EVM can test the audio performance of the THS4524 as a drive amplifier. The standard PCM4204EVM is provided with four OPA1632 fullydifferential amplifiers, which use the same device pinout as the THS4524. For testing, one of these amplifiers is replaced with a THS4524 device in same package (MSOP), and the power supply changes to a single-supply +5V. Figure 79 shows the modifications made to the circuit. Note the resistor connecting the V_{OCM} input of the THS4524 to the input commonmode drive from the PCM4204 is shown removed and is optional; no performance change was noted with it connected or removed. The THS4524 is operated with a +5-V single-supply so the output common-mode defaults to +2.5 V as required at the input of the PCM4204. The EVM power connections were modified by connecting positive supply inputs,

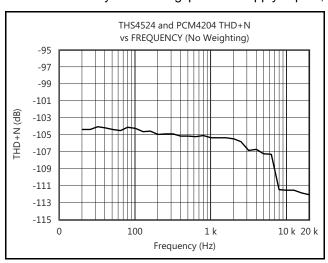


Figure 77. THS4524 and PCM4204: THD+N versus Frequency with No Weighting

+15 V, +5 VA and +5 VD, to a +5-V external power supply (EXT +3.3 was not used) and connecting -15 V and all ground inputs to ground on the external power supply. Note only one external +5-V supply was needed to power all devices on the EVM.

A SYS-2722 Audio Analyzer from Audio Precision (AP) provides an analog audio input to the EVM; the PCM-formatted digital output is read by the digital input on the AP.

Data were taken using a $256 \cdot f_S$ system clock to achieve $f_S = 48 \cdot kHz$ measurements, and audio output uses PCM format. Other data rates and formats are expected to show similar performance in line with that shown in the product data sheet.

Figure 77 shows the THD+N vs Frequency response with no weighting; Figure 78 shows an FFT of the output with 1-kHz input tone. Input signals to the PCM4204 for these tests is 0.5 dBFS. Dynamic range is also tested at -60 dBFS, $f_{\rm IN}=1$ kHz, and A-weighted. Table 4 summarizes testing results using the THS4524 together with the PCM4204 versus typical data sheet performance measurements, and show that it make an excellent drive amplifier for this ADC.

The test circuit shown in Figure 79 has a gain = 0.27 and attenuates the input signal. For applications that require higher gain, the circuit was modified to gains of G = 1, G = 2, and G = 5 by replacing the feedback resistors (R33 and R34) and re-tested to show performance.

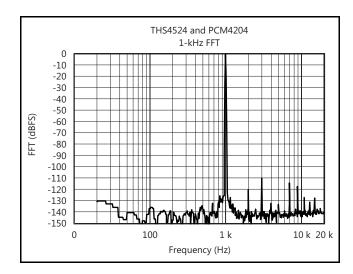


Figure 78. THS4524 and PCM4204 1-kHz FFT



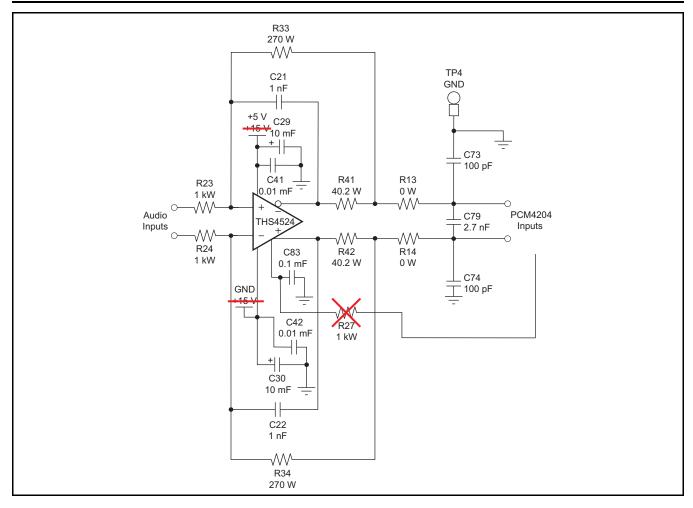


Figure 79. THS4524 and PCM4204 Test Circuit

Table 4. 1-kHz AC Analysis: Test Circuit versus PCM4204 Data Sheet Typical Specifications ($f_S = 48 \text{ kSPS}$)

Configuration	Tone	THD+N	Dynamic Range
THS4524 and PCM4204	1 kHz	-106 dBc	117 dB
PCM4204 Data sheet (typ)	1 kHz	-105 dBc	118 dB



Figure 80 shows the THS4524 and PCM4204 THD+N versus frequency with no weighting at higher gains.

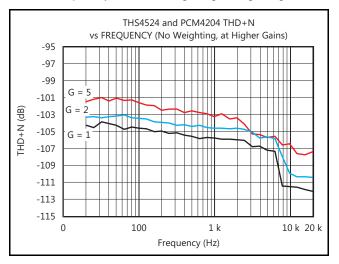


Figure 80. THS4524 and PCM4204: THD+N versus Frequency with No Weighting at Higher Gains

Audio ADC Driver Performance: THS4524 and PCM3168 Combined Performance

The THS4524 is also tested as the drive amplifier for the PCM3168A ADC input. The PCM3168A is a highperformance, single-chip, 24-bit, 6-in/8-out, audio coder/decoder (codec) with single-ended differential selectable analog inputs and differential outputs. The six-channel, 24-bit ADC employs a $\Delta\Sigma$ modulator and supports 8-kHz to 96-kHz sampling rates and a 16-bit/24-bit width digital audio output word on the audio interface. The eight-channel, 24-bit digital-to-analog converter (DAC) employs a $\Delta\Sigma$ modulator and supports 8-kHz to 192-kHz sampling rates and a 16-bit/24-bit width digital audio input word on the audio interface. Each audio interface supports I²S[™], left-/right-justified, and DSP formats with 16bit/24-bit word width. In addition, the PCM3168A supports the time-division-multiplexed (TDM) format.. The PCM3168A provides flexible serial port interface and many other advanced features. Refer to the PCM3168A product data sheet for more information.

The PCM3168A EVM is used to test the audio performance of the THS4524 as a drive amplifier. The standard PCM3168A EVM is provided with OPA2134 op amps that are used to convert single-ended inputs to differential to drive the ADC. For testing, the op amp output series resistors are removed from one of the channels and a THS4524, mounted on its standard EVM, is connected to the ADC inputs via short coaxial cables. The THS4524

EVM is configured for both differential inputs as shown in Figure 61 and for single-ended input as shown in Figure 62 with 1-k Ω resistors for R_F and R_G, and $24.9-\Omega$ resistors in series with each output to isolate the outputs from the reactive load of the coaxial cables. To limit the noise from the external EVM and cables, a 2.7-nF capacitor is placed differentially across the PCM3168A inputs. The THS4524 is operated with a single-supply +5-V supply so the output common-mode of the THS4524 defaults to +2.5 V as required at the input of the PCM3168A. The PCM3168A EVM is configured and operated as described in the PCM3168AEVM User Guide. The ADC was tested with an external THS4524 EVM with both single-ended input and differential inputs. In both configurations, the results are the same. Figure 81 shows the THD+N versus frequency and Table 5 compares the result to the PCM3168 data sheet typical specification at 1 kHz. Both graphs show that it makes an excellent drive amplifier for this ADC. Note: a 2700 series Audio Analyzer from Audio Precision is used to generate the input signals to the THS4524 and to analyze the digital data from the PCM3168.

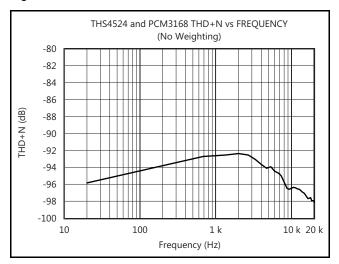


Figure 81. THS4524 and PCM3168: THD+N versus Frequency with No Weighting

Table 5. 1-kHz AC Analysis: Test Circuit vs PCM3168 Data Sheet Typical Specifications (f_S = 48 kSPS)

Configuration	Tone	THD+N
THS4524 and PCM3168	1 kHz	−92.6 dBc
PCM3168 Data sheet (typ)	1 kHz	-93 dBc



ADC Driver Performance: THS4524 and ADS1278 Combined Performance

The THS4524 provides excellent performance when driving high-performance $\Delta\Sigma$ and successive approximation register (SAR) ADCs in audio and industrial applications using a single 3-V to 5-V power supply. To show achievable performance, the THS4524 is tested as the drive amplifier for the ADS1278 24-bit ADC. The ADS1278 offers excellent ac and dc performance, with four selectable operating

modes from 10 kSPS to 128 kSPS to enable the user to fine-tune performance and power for specific application needs. The circuit shown in Figure 82 was used to test the performance. Data were taken using the High-Resolution mode (52 kSPS) of the ADS1278 with input frequencies at 1 kHz and 10 kHz and signal levels 1/2 dB below full-scale (-0.5 dBFS). FFT plots showing the spectral performance are given in Figure 83 and Figure 84; tabulated ac analysis results are shown in Table 6 and compared to the ADS1278 data sheet typical performance specifications.

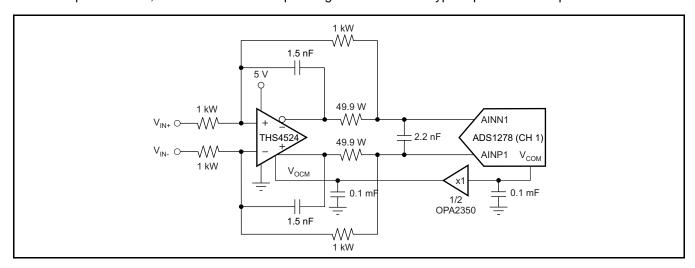
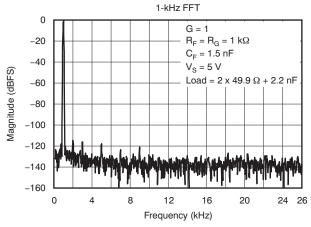
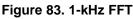


Figure 82. THS4524 and ADS1278 (Ch 1) Test Circuit





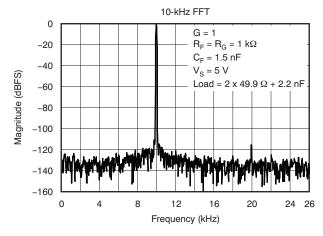


Figure 84. 10-kHz FFT

Table 6. AC Analysis

Configuration	Tone	Signal (dBFS)	SNR (dBc)	THD (dBc)	SINAD (dBc)	SFDR (dBc)
THS4524 and	1 kHz	-0.5	109	-108	105	114
ADS1278	10 kHz	-0.5	102	-110	101	110
ADS1278 Data sheet (typ)	1 kHz	-0.5	110	-108	_	109

Product Folder Links : THS4524-EP



ADC Driver Performance: THS4524 and ADS8321 Combined Performance

To demonstrate achievable performance, the THS4524 is tested as the drive amplifier for the ADS8321 16-bit SAR ADC. The ADS8321 offers excellent ac and dc performance, with ultra-low power and small size. The circuit shown in Figure 85 was used to test the performance.

Data were taken using the ADS8321 at 100 kSPS with input frequencies of 2 kHz and 10 kHz and signal levels that were -0.5 dBFS. FFT plots that illustrate the spectral performance are given in Figure 86 and Figure 87. Tabulated ac analysis results are listed in Table 7 and compared to the ADS8321 data sheet typical performance.

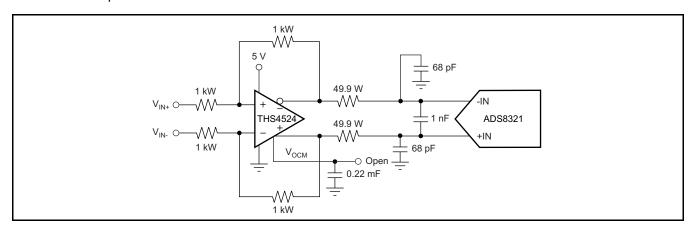
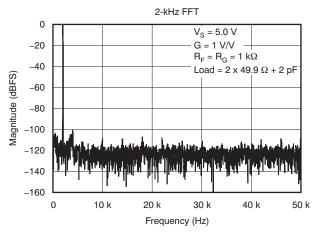


Figure 85. THS4524 and ADS8321 Test Circuit



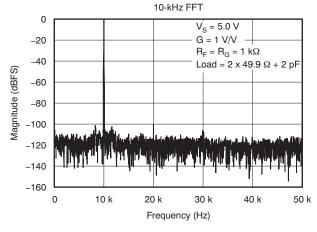


Figure 86. 2-kHZ FFT

Figure 87. 10-kHz FFT

Table 7. AC Analysis

Configuration	Tone	Signal (dBFS)	SNR (dBc)	THD (dBc)	SINAD (dBc)	SFDR (dBc)
THS4524 and	2 kHz	-0.5	86.7	-97.8	86.4	100.7
ADS8321	10 kHz	-0.5	85.2	-98.1	85.2	102.2
ADS8321 Data sheet (typ)	10 kHz	-0.5	87	-86	84	86

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EVM AND LAYOUT RECOMMENDATIONS

Figure 88 shows the THS4524EVM schematic. PCB layers 1 through 4 are shown in Figure 89; Table 8 lists the bill of materials for the THS4524EVM as supplied from TI. It is recommended to follow the layout of the external components near to the amplifier, ground plane construction, and power routing as closely as possible. Follow these general guidelines:

- 1. Signal routing should be direct and as short as possible into and out of the op amp circuit.
- 2. The feedback path should be short and direct.
- 3. Ground or power planes should be removed from directly under the amplifier input and output pins.
- 4. An output resistor is recommended in each output lead, placed as near to the output pins as possible.
- 5. Two 0.1-µF power-supply decoupling capacitors should be placed as near to the power-supply pins as possible.
- 6. Two 10-μF power-supply decoupling capacitors should be placed within 1 inch of the device and can be shared among multple analog devices.
- 7. A 0.22- μF capacitor should be placed between the V_{OCM} input pin and ground near to the pin. This capacitor limits noise coupled into the pin.
- 8. The \overline{PD} pin uses TTL logic levels; a bypass capacitor is not necessary if actively driven, but can be used for robustness in noisy environments whether driven or not.
- 9. If input termination resistors R_{10} and R_{11} are used, a single point connection to ground on L2 is recommended.

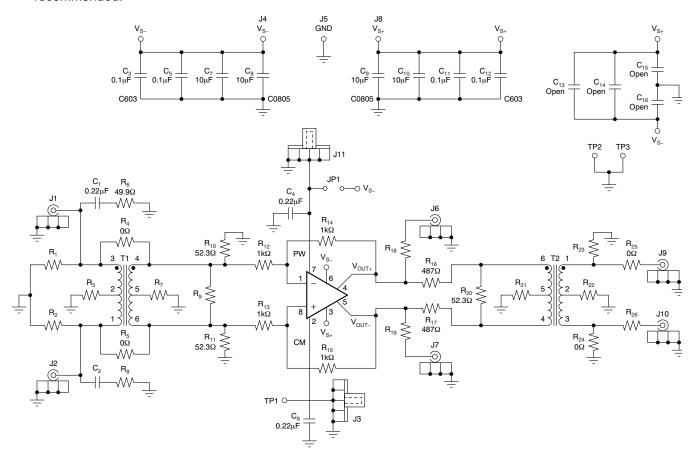


Figure 88. THS4524EVM: Schematic

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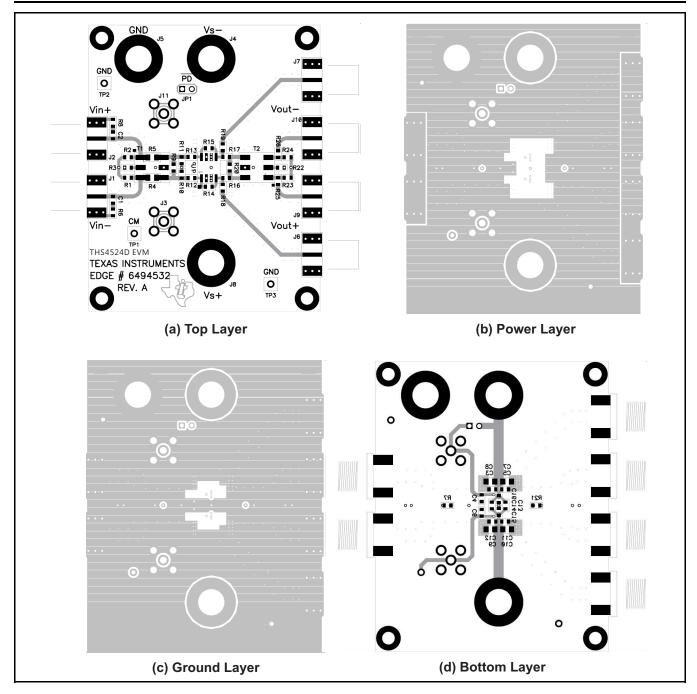


Figure 89. THS4524EVM: Layer 1 to Layer 4 Images



Table 8. THS4524EVM Parts List

REFERENCE MANUFACTURER									
ITEM	DESCRIPTION	SMD SIZE	DESIGNATOR	QTY	PART NUMBER				
1	Capacitor, 10.0 µF, ceramic, X5R, 6.3 V	0805	C7, C8, C9, C10	4	(AVX) 08056D106KAT2A				
2	Capacitor, 0.1 µF, ceramic, X7R, 16 V	0603	C3, C5, C11, C12	4	(AVX) 0603YC104KAT2A				
3	Capacitor, 0.22 µF, ceramic, X7R, 10 V	0603	C1, C4, C6	3	(AVX) 0603ZC224KAT2A				
4	Open	0603	C2, C13, C14, C15, C16	5					
5	Open	0603	R1, R2, R3, R7, R8, R9, R18, R19, R21, R22, R23, R26	12					
6	Resistor, 0 Ω	0603	R24, R25	2	(ROHM) MCR03EZPJ000				
7	Resistor, 49.9 Ω, 1/10W, 1%	0603	R6	1	(ROHM) MCR03EZPFX49R9				
8	Resistor, 52.3 Ω, 1/10W, 1%	0603	R10, R11, R20	3	(ROHM) MCR03EZPFX52R3				
9	Resistor, 487 Ω, 1/10W, 1%	0603	R16, R17	2	(ROHM) MCR03EZPFX4870				
10	Resistor, 1k Ω, 1/10W, 1%	0603	R12, R13, R14, R15	4	(ROHM) MCR03EZPFX1001				
11	Resistor, 0 Ω	0805	R4, R5	2	(ROHM) MCR10EZPJ000				
12	Open		T1	1					
13	Transformer, RF		T2	1	(MINI-CIRCUITS) ADT1-1WT				
14	Jack, Banana receptance, 0.25-in dia. hole		J4, J5, J8	3	(SPC) 813				
15	Open		J1, J3, J6, J7, J10, J11	6					
16	Connector, edge, SMA PCB jack		J2, J9	2	(JOHNSON) 142-0701-801				
17	Header, 0.1 in CTRS, 0.025-in sq. pins	2 POS.	JP1	1	(SULLINS) PBC36SAAN				
18	Shunts		JP1	1	(SULLINS) SSC02SYAN				
19	Test point, Red		TP1	1	(KEYSTONE) 5000				
20	Test point, Black		TP2, TP3	2	(KEYSTONE) 5001				
21	IC, THS4524		U1	1	(TI) THS4524D				
22	Standoff, 4-40 hex, 0.625 in length			4	(KEYSTONE) 1808				
23	Screw, Phillips, 4-40, .250 in			4	SHR-0440-016-SN				
24	Board, printed circuit			1	(TI) EDGE# 6494532				

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EVM Warnings and Restrictions

It is important to operate this EVM within the input voltage range of 3 V to 5.5 V and the output voltage range of 3 V to 5.5 V.

Exceeding the specified input range may cause unexpected operation and/or irreversible damage to the EVM. If there are questions concerning the input range, please contact a TI field representative prior to connecting the input power.

Applying loads outside of the specified output range may result in unintended operation and/or possible permanent damage to the EVM. Please consult the EVM User's Guide prior to connecting any load to the EVM output. If there is uncertainty as to the load specification, please contact a TI field representative.

During normal operation, some circuit components may have case temperatures greater than 125°C. The EVM is designed to operate properly with certain components above 125°C as long as the input and output ranges are maintained. These components include but are not limited to linear regulators, switching transistors, pass transistors, and current sense resistors. These types of devices can be identified using the EVM schematic located in the EVM User's Guide. When placing measurement probes near these devices during operation, please be aware that these devices may be very warm to the touch.

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Product Folder Links: THS4524-EP

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PACKAGING INFORMATION

Orderable part number	Status	Material type	Package Pins	Package qty Carrier	RoHS (3)	Lead finish/ Ball material	MSL rating/ Peak reflow	Op temp (°C)	Part marking (6)
THS4524MDBTREP	Active	Production	TSSOP (DBT) 38	2000 LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-55 to 125	THS4524EP
V62/12612-01XE	Active	Production	TSSOP (DBT) 38	2000 LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-55 to 125	THS4524EP

⁽¹⁾ Status: For more details on status, see our product life cycle.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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OTHER QUALIFIED VERSIONS OF THS4524-EP:

Catalog: THS4524

⁽²⁾ Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

⁽³⁾ RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

⁽⁴⁾ Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

⁽⁵⁾ MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

⁽⁶⁾ Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.



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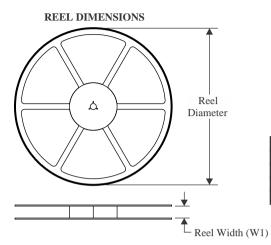
NOTE: Qualified Version Definitions:

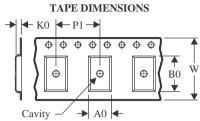
 $_{\bullet}$ Catalog - TI's standard catalog product

PACKAGE MATERIALS INFORMATION

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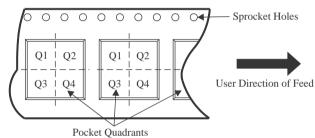
TAPE AND REEL INFORMATION





	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE

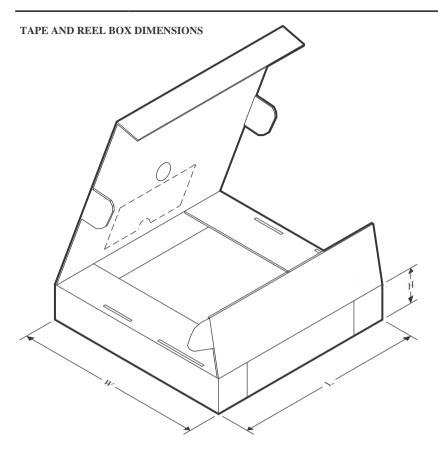


*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
THS4524MDBTREP	TSSOP	DBT	38	2000	330.0	16.4	6.75	10.1	1.8	12.0	16.0	Q1

PACKAGE MATERIALS INFORMATION

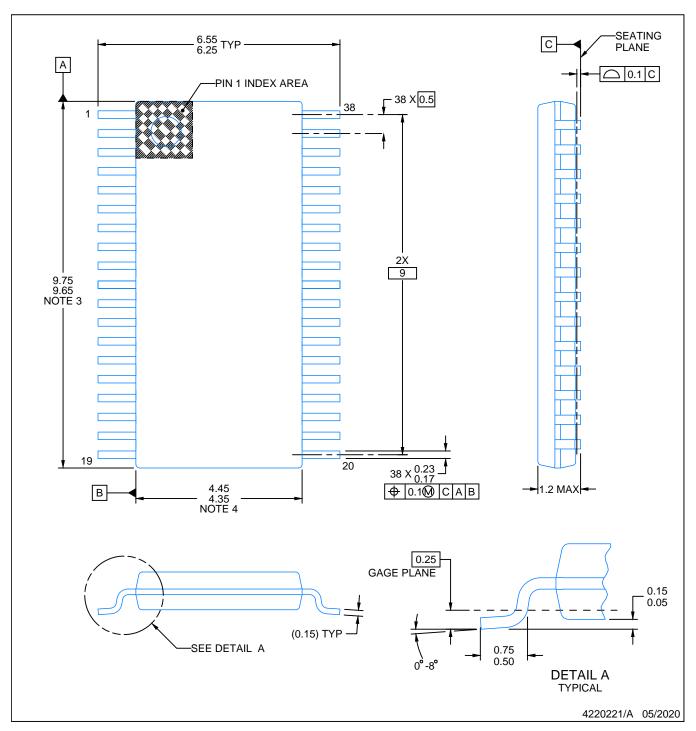
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*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
THS4524MDBTREP	TSSOP	DBT	38	2000	353.0	353.0	32.0

SMALL OUTLINE PACKAGE

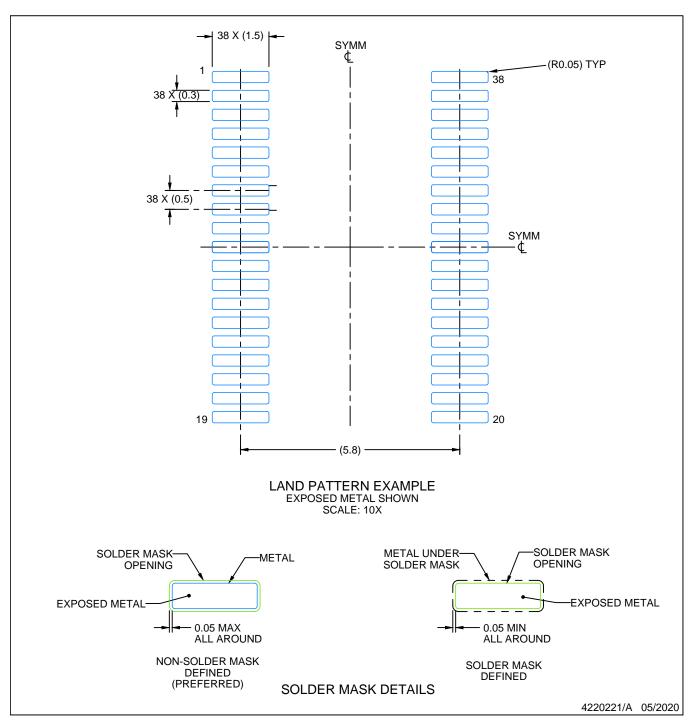


NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.
- 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.



SMALL OUTLINE PACKAGE



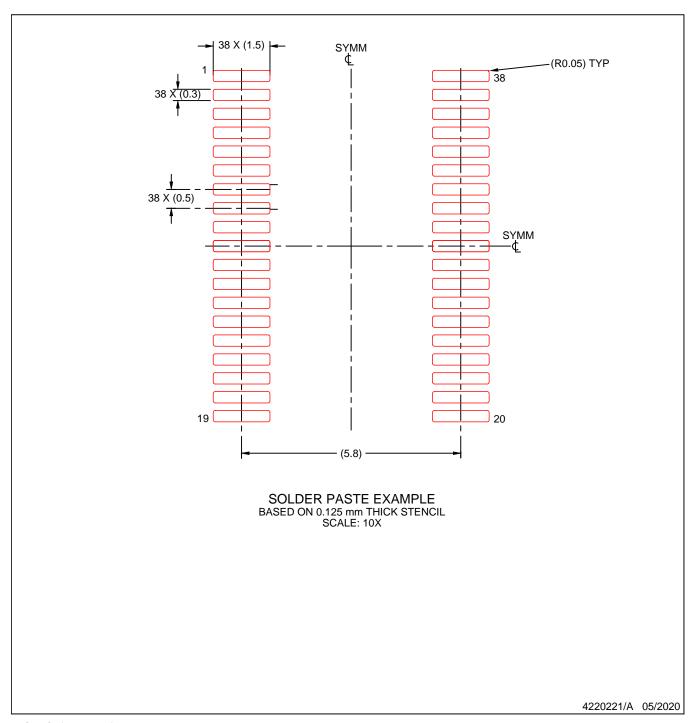
NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE PACKAGE



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



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